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Application/Control No.	Applicant(s)/ Reexamination	
10/541,028	SUKENO ET	ΓAL.
Examiner	Art Unit	
David H. Chu	2628	DHC

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Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (USPAT, US-PGPUB, USOCR, EPO, IBM_TDB)	2/23/2008	DHC
EAST (text search only - see search history printout)	2/23/2008	DHC
Inventor Search(No double patent)	2/23/2008	DHC
345/ 629 (text search only - see search history printout)	2/23/2008	DHC